
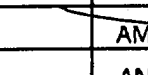
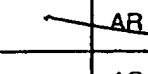
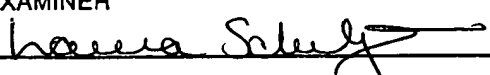

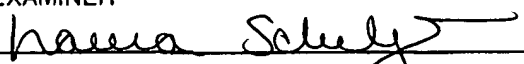
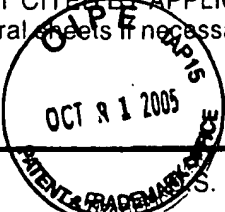



Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1533		SERIAL NO. 09/754,926		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Kie Y. Ahn et al.				
				FILING DATE January 4, 2001		GROUP 2813		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Sub- class	Filing Date If Appropriate	
	AA	6,809,010 B1	10-2004	Kinoshita et al.	—	—	—	
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Sub- class	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER 				DATE CONSIDERED 7/6/06				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

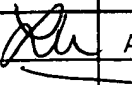
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1533		SERIAL NO. 09/754,926	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Kie Y. Ahn et al.			
					FILING DATE January 4, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Sub- class	Filing Date If Appropriate	
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FOREIGN PATENT DOCUMENTS								
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							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR		Wikipedia (an online dictionary) (http://en.wikipedia.org/wiki/sapphire)					
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EXAMINER 				DATE CONSIDERED 7/6/06				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

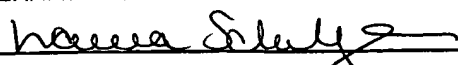
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				FILING DATE January 4, 2001		GROUP 2813	



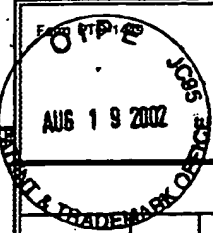
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Document Number	Date	Country	Class	Sub-class	Translation		
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	AM	58-153372	09-1983	Japan	—	—	
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		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DO. NO. M122-1533		SERIAL NO. 09754,926	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						APPLICANT Kie Y. Ahn et al.	
						FILING DATE January 4, 2001	
						GROUP 2813	
U.S. PATENT DOCUMENTS							
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	Document Number	Date	Country	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
EK	AR		H.F. Luan et al., "High Quality Ta_2O_5 Gate Dielectrics with T_{ox} < 10Å" International Electron Devices Meeting, pgs. 141-144, 1999. The year of publication is sufficiently early such that the month is not in issue.				
EK	AS		O. Zywicki et al., "Effect of Plasma Activation on the Phase Transformations of Aluminum Oxide" Surface and Coatings Technology, Vol 76/77, Iss 1/3, pgs. 754-762, 1993. The year of publication is sufficiently early such that the month is not in issue.				
EK	AT		N. Chand et al., "Tunability of Intrinsic Stress in SiO_2 Dielectric Films Formed by Molecular Beam Deposition". Materials Research Society Symposia Proceedings, Vol 356, pgs. 193-200, 1993. The year of publication is sufficiently early such that the month is not in issue.				
EXAMINER		DATE CONSIDERED					
Eric K. H. H.		10/5/02					
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				GROUP 2813			
U.S. PATENT DOCUMENTS							
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	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
EX	AR		Wolf, S., "Silicon Processing for the VLSI Era", Vol. 2: Process Integration, 1990 Lattice Press, Sunset Beach, CA,				
			pp. 332-333.				
	AS						
	AT						
EXAMINER Erik K. Lili				DATE CONSIDERED 2/1/03			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							